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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10028429	FILING DATE 12/28/2001	CLASS 438	SUBCLASS 197	GAU 2823	EXAMINER K. Nanyan
**APPLICANTS: Hashimoto Koichi, Matsunaga Daisuke, Aoyama Masahiko					
**CONTINUING DATA VERIFIED: THIS APPLICATION IS A DIV OF 08/787 451 01/22/1997					
** FOREIGN APPLICATIONS VERIFIED: JAPAN HEI 5-176956 07/16/1993					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiner's initials				ATTORNEY DOCKET NO 107317-00039	
TITLE : Dry etching with reduced damage to MOS device					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner		CLAIMS ALLOWED	
				Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner		DRAWING	
Amount Due	Date Paid			Sheets Drawg.	Figs. Drawg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		Application Examiner	
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